


<b>Search Notes</b> 	<b>Application/Control No.</b> 10758863	<b>Applicant(s)/Patent Under Reexamination</b> STASZEWSKI ET AL.
	<b>Examiner</b> Flores, Leon	<b>Art Unit</b> 2611

### SEARCHED

Class	Subclass	Date	Examiner
375	224, 226, 375, 376	3/22/2007	LF
327	141, 147, 156	3/22/2007	LF
455	423, 425	3/12/2008	LF

### SEARCH NOTES

Search Notes	Date	Examiner
Consulted with SPE Chieh Fan in regards to the patentability of claim 1 & 32	3/22/2007	LF
Consulted with SPE David Payne in regards to the patentability of the claims.	3/26/2007	LF
Checked for double patenting.	3/22/2007	LF
Consulted with SPE David Payne in regards to the amendments.	9/10/2007	LF
Consulted with SPE David Payne in regards to the AF.	11/28/2007	LF
Consulted with SPE David Payne in regards to the references used to reject the claims.	3/19/2008	LF
Consulted with SPE David Payne in regards to the arguments.	12/19/2008	LF
Consulted with SPE David Payne in regards to the new ground of rejection.	9/10/2009	LF

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

/L. F./  
Examiner, Art Unit 2611